

<b>Notice of References Cited</b>	Application/Control No. 09/537,863		Applicant(s)/Patent Under Reexamination FUNAHASHI ET AL.	
	Examiner Devona E. Faulk		Art Unit 2644	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,924,963	05-1990	Polk, Matthew S.	181/144
*	B	US-4,905,788	03-1990	Lanternier, Philippe	181/144
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 800330 A2	10-1997	European Patent	FUNAHASHI et al.	H04R 01/28
*	O	GB 2260464 A	04-1993	United Kingdom	HOBELSBERGER et al.	H04R 01/20
*	P	GB 2226214 A	06-1990	United Kingdom	GADEA, VESES JAVIER	H04R 01/30
*	Q	JP 01130697 A	05-1989	Japan	SAKAMOTO, KAZUHIRO	H04R 01/28
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.